



ALPHA & OMEGA
SEMICONDUCTOR

AONA66813

80V N-Channel AlphaSGT2™

General Description

- AlphaSGT2™ N-Channel Power MOSFET
- Low $R_{DS(ON)}$
- Standard Level
- Low Gate Charge
- RoHS 2.0 and Halogen-Free Compliant

Product Summary

V_{DS}	80V
I_D (at $V_{GS}=10V$)	216A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 2.2mΩ
$R_{DS(ON)}$ (at $V_{GS}=8V$)	< 2.5mΩ

Applications

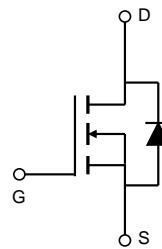
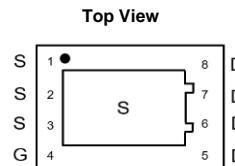
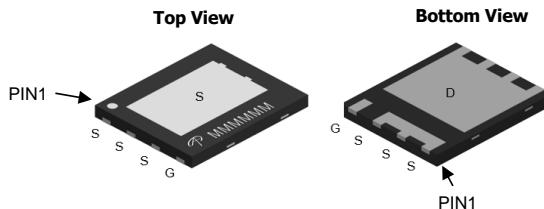
- DCDC Brick Module
- Synchronous Rectification

100% UIS Tested
100% R_g Tested

Max $T_j=175^{\circ}C$



DFN5X6



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AONA66813	DFN 5x6	Tape & Reel	5000

Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	80	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^A	I_D	216	A
$T_C=100^{\circ}C$		152	
Pulsed Drain Current ^C	I_{DM}	864	A
Continuous Drain Current ^A	I_{DSM}	40	A
$T_A=70^{\circ}C$		34	
Avalanche Current ^C	I_{AS}	70	A
Avalanche energy ^C	E_{AS}	245	mJ
Power Dissipation ^B	P_D	214	W
$T_C=100^{\circ}C$		107	
Power Dissipation ^A	P_{DSM}	7.5	W
$T_A=70^{\circ}C$		5.2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$t \leq 10s$	$R_{\theta JA}$	15	°C/W
Maximum Junction-to-Ambient ^{A,D}	Steady-State	$R_{\theta JA}$	40	°C/W
Maximum Junction-to-Case,bottom	Steady-State	$R_{\theta JC}$	0.4	°C/W
Maximum Junction-to-Case,top	Steady-State	$R_{\theta JC}$	0.35	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	80			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=80\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.6	3.2	3.8	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		1.8	2.2	$\text{m}\Omega$
		$V_{GS}=8\text{V}, I_D=20\text{A}$		3	3.6	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		62		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current				200	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=40\text{V}, f=1\text{MHz}$		5800		pF
C_{oss}	Output Capacitance			1570		pF
C_{rss}	Reverse Transfer Capacitance			24		pF
R_g	Gate resistance	$f=1\text{MHz}$	0.7	1.5	2.3	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=40\text{V}, I_D=20\text{A}$		75	105	nC
Q_{gs}	Gate Source Charge			24		nC
Q_{gd}	Gate Drain Charge			14		nC
Q_{oss}	Output Charge	$V_{GS}=0\text{V}, V_{DS}=40\text{V}$		118		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=40\text{V}, R_L=2\Omega, R_{GEN}=3\Omega$		17		ns
t_r	Turn-On Rise Time			6.9		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			37		ns
t_f	Turn-Off Fall Time			9.6		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, di/dt=500\text{A}/\mu\text{s}$		34		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, di/dt=500\text{A}/\mu\text{s}$		165		nC

A. The value of R_{iJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{iJA} \leq 10\text{s}$ and the maximum allowed junction temperature of 175°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D. The R_{iJA} is the sum of the thermal impedance from junction to case R_{iJC} and case to ambient.

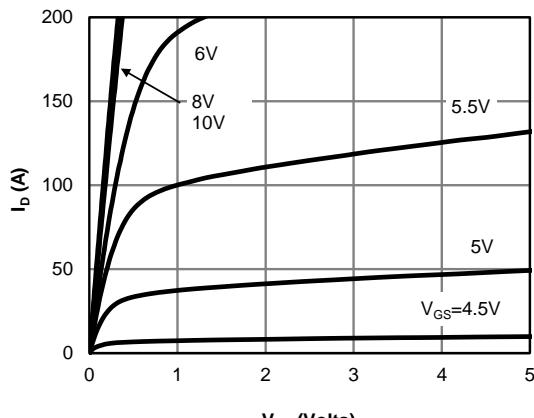
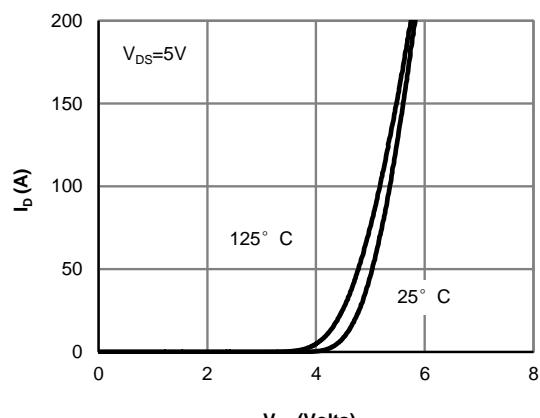
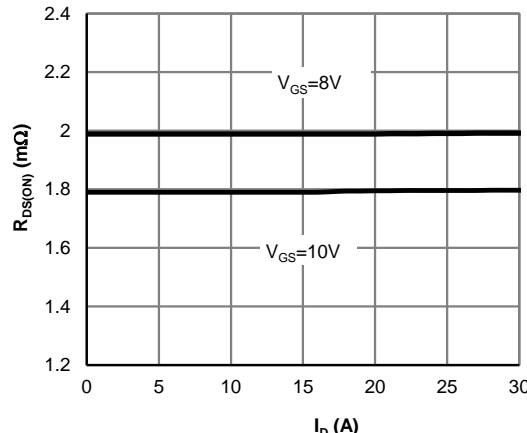
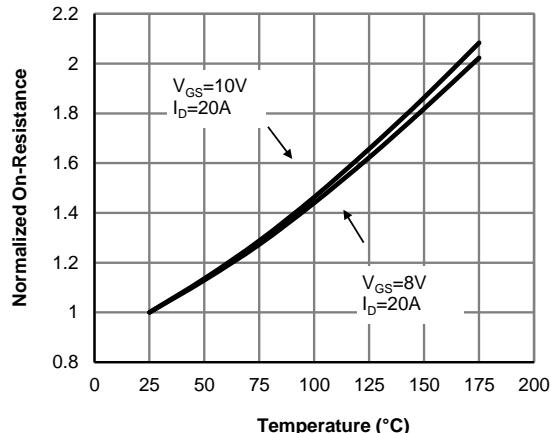
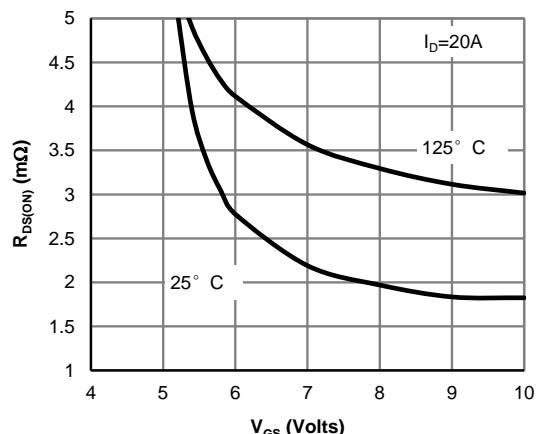
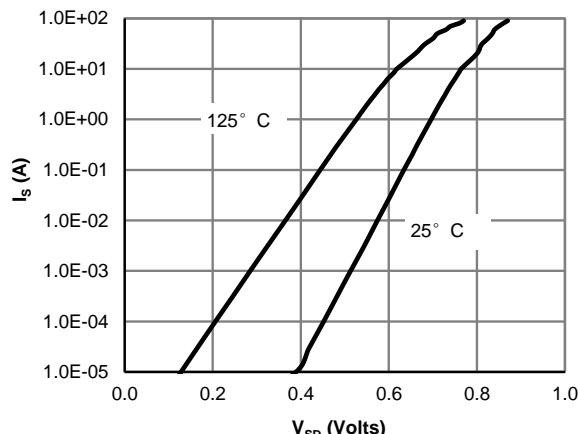
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

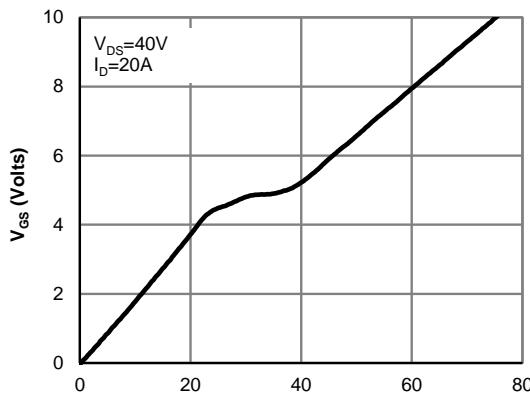
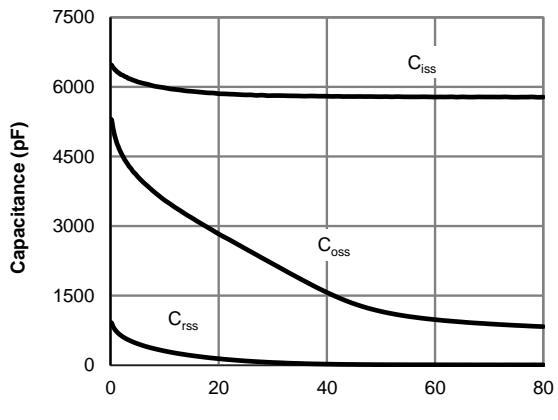
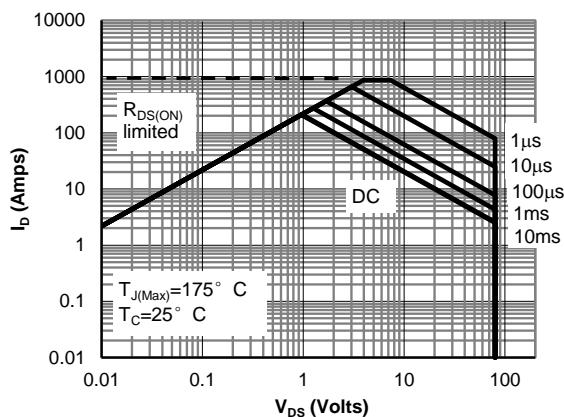
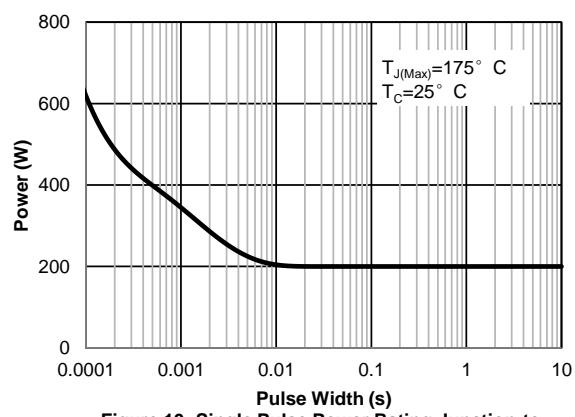
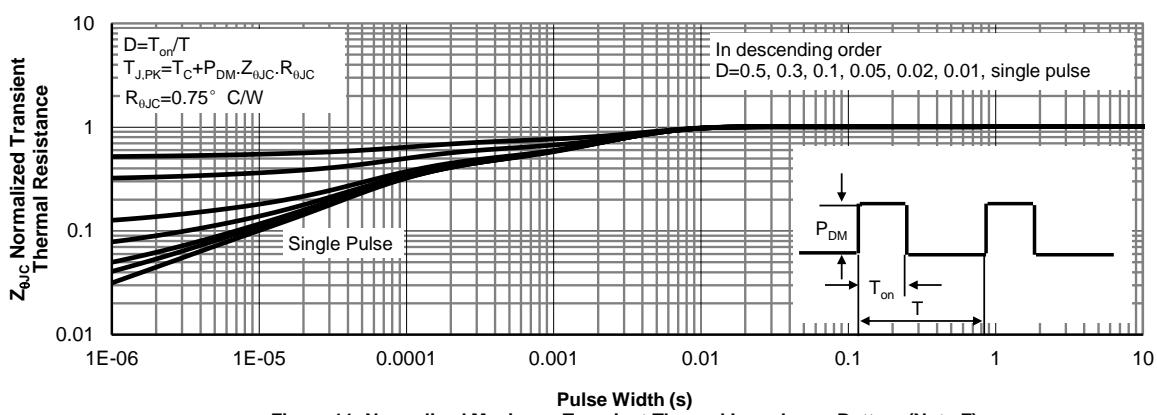
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$. The SOA curve provides a single pulse rating.

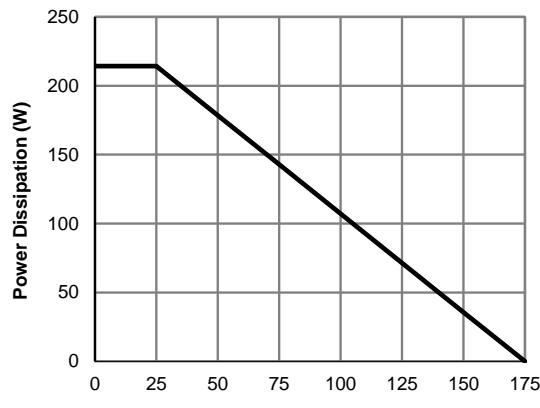
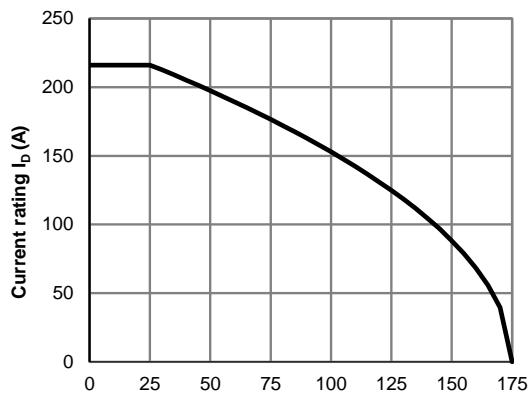
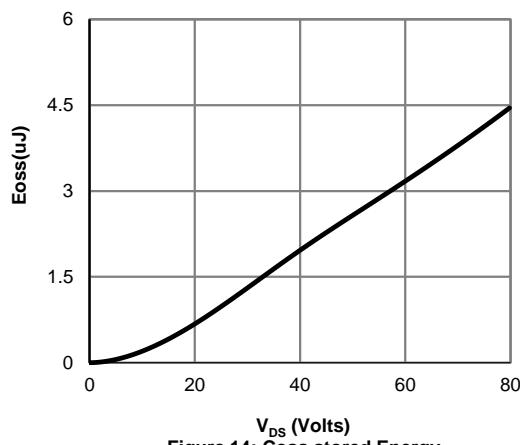
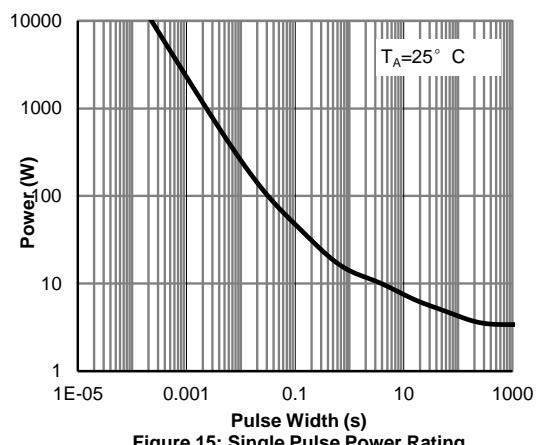
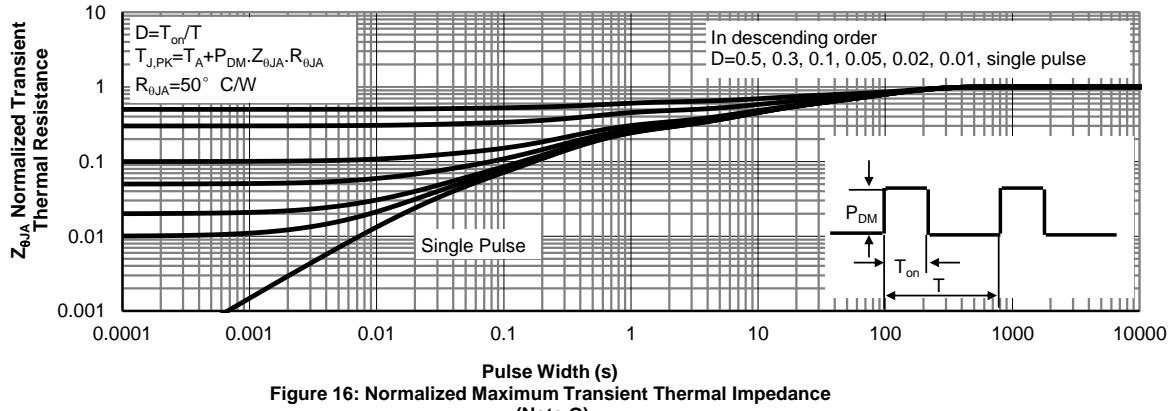
G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case-Bottom (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance-Bottom (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 12: Power De-rating (Note F)

Figure 13: Current De-rating (Note F)

Figure 14: Coss stored Energy

**Figure 15: Single Pulse Power Rating
Junction-to-Ambient (Note G)**

**Figure 16: Normalized Maximum Transient Thermal Impedance
(Note G)**

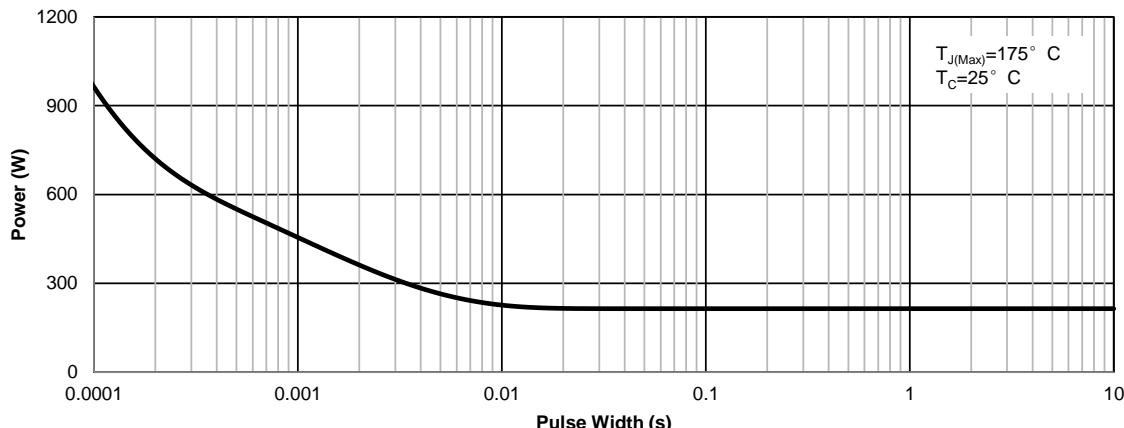
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 17: Single Pulse Power Rating Junction-to-Case-Top (Note F)

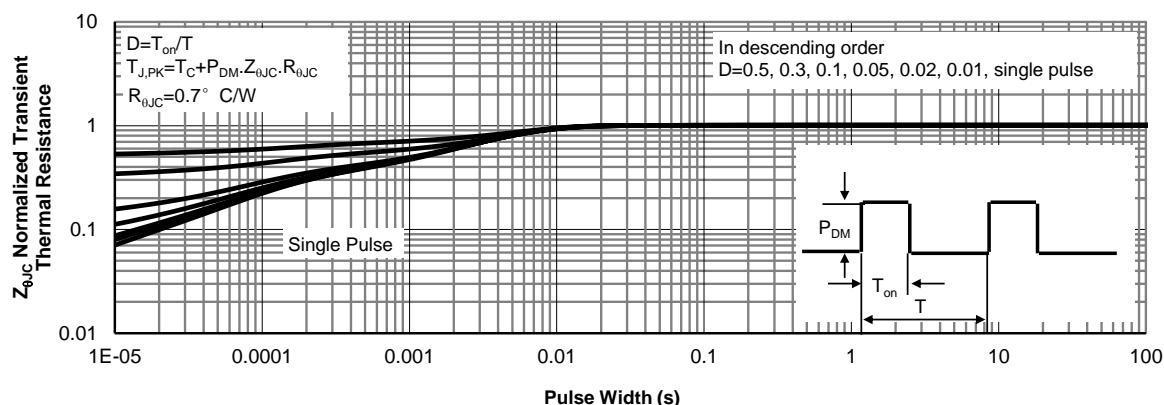


Figure 18: Normalized Maximum Transient Thermal Impedance-Top (Note F)

Figure A: Gate Charge Test Circuit & Waveforms

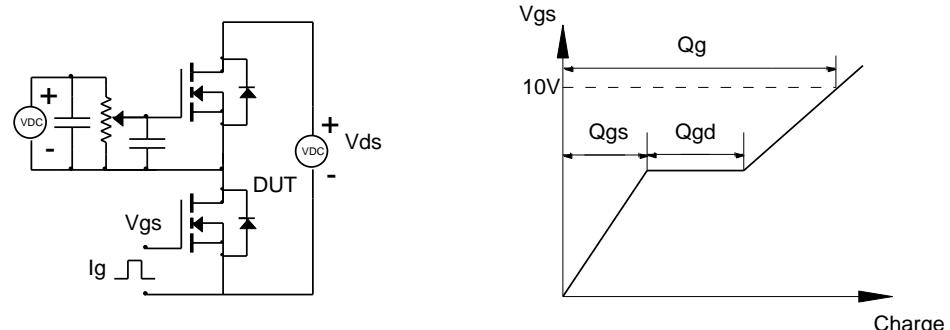


Figure B: Resistive Switching Test Circuit & Waveforms

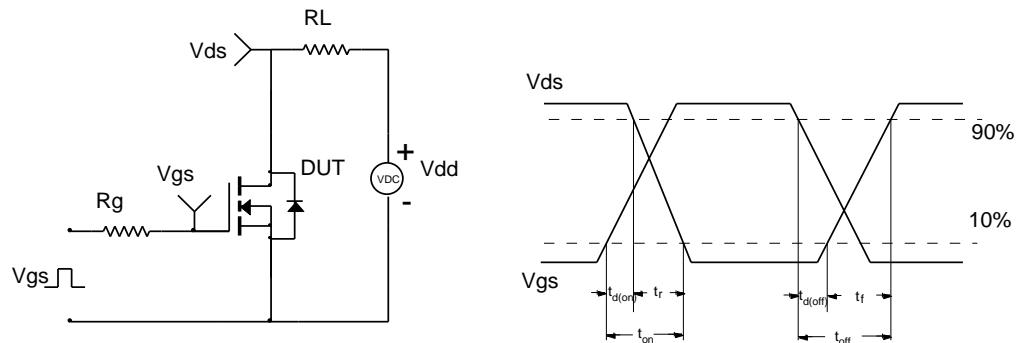


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

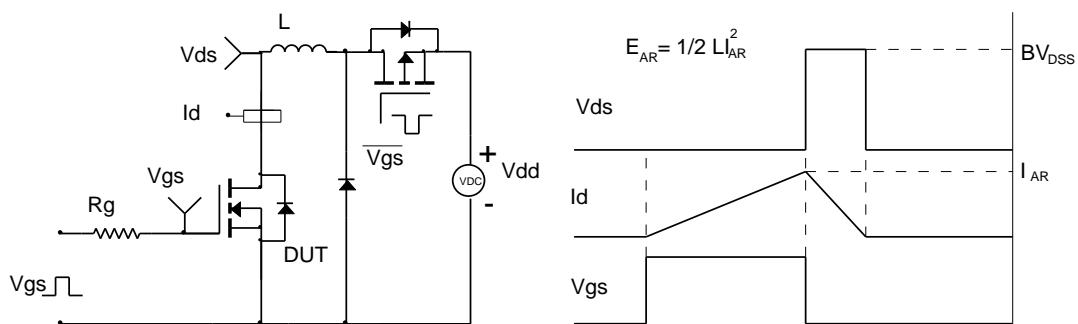


Figure D: Diode Recovery Test Circuit & Waveforms

